

U.S. Department of Commerce, Patent and Trademark Office					Atty Docket No.		Serial No.	
					M-10696 US		09/742,029	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT					Applicant(s),			
(Use several sheets if necessary)					Gouheng, Zhao et al.			
					Filing Date		Group	
					December 20, 2000		2877	

U.S. Patent Documents							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
JS	AA	5,438,415	8/1/95	Kazama et al.			
	AB	5,793,480	8/11/98	Lacey et al.			
	AC	5,910,841	6/8/99	Masao			
JS	AD	6,134,011	10/17/00	Klein et al.			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

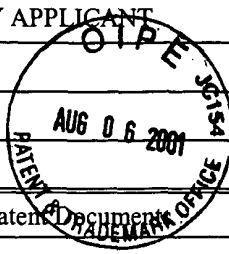
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
	AQ	International Search Report, 2002.
	AR	
	AS	

Examiner <i>Yanwei</i>	Date Considered <i>9/23/02</i>
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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(Use several sheets if necessary)					GUOHENG ZHAO ET AL.			
					Filing Date		Group	
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U.S. Patent & Trademark Office

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
1/5	AA	5,517,312	5/14/96	Finarov	356	386	4/1/94
	AB	5,607,800	3/4/97	Ziger	430	8	2/15/95
	AC	5,739,909	4/14/98	Blayo et al.	356	369	10/10/95
	AD	5,764,365	6/9/98	Finarov	356	381	5/13/96
	AE	5,867,276	2/2/99	McNeil et al.	356	445	3/7/97
	AF	5,963,329	10/5/99	Conrad et al.	356	372	10/31/97
3/5	AG	6,100,985	8/8/00	Scheiner et al.	356	381	3/12/99
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)	
AQ	"Ultraviolet-visible ellipsometry for process control during the etching of submicrometer features," N. Blayo et al., <i>Journal of the Optical Society of America A</i> , Vol. 12, No. 3, March 1995, pp. 591-599
AR	
AS	

Examiner <i>Julian S. [Signature]</i>	Date Considered <i>9/23/02</i>
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